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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/802,641	03/16/2004	Jian Lu	710240-577	3947
59582 7590 07/18/2007 DICKINSON WRIGHT PLLC 38525 WOODWARD AVENUE			EXAMINER	
			KRAUSE, JUSTIN MITCHELL	
SUITE 2000 BLOOMFIELI	O HILLS, MI 48304-2970		ART UNIT	PAPER NUMBER
	•		3682	
			MAIL DATE	DELIVERY MODE
		•	07/18/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.



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APPLICATION NO./ CONTROL NO.	FILING DATE	FIRST NAMED INVENTOR / PATENT IN REEXAMINATION		ATTORNEY DOCKET NO.
10802641	3/16/2004	LU ET AL.	710240-577	
DICKINSON WRIGHT PLLC 38525 WOODWARD AVENUE			EXAMINER	
			Justin Krause	
SUITE 2000 BLOOMFIELD HILLS, MI 48304-2970			ART UNIT	PAPER
			3682	20070712

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Commissioner for Patents

The reply filed on April 30, 2007 is not fully responsive to the prior Office Action because of the following omission(s) or matter(s): The remarks regarding the rejections under 112, 2nd paragraph fail to address the rejections made in the Office Action mailed January 30, 2007. Specifically, Applicant has failed to explain how claims 26-29 are readable on the elected embodiment. See 37 CFR 1.111. Since the above-mentioned reply appears to be bona fide, applicant is given ONE (1) MONTH or THIRTY (30) DAYS from the mailing date of this notice, whichever is longer, within which to supply the omission or correction in order to avoid abandonment. EXTENSIONS OF THIS TIME PERIOD MAY BE GRANTED UNDER 37 CFR 1.136(a).

7/12/67

Thomas R. Hannon Primary Examiner